

## 74ACQ574 • 74ACTQ574 Quiet Series™ Octal D-Type Flip-Flop with 3-STATE Outputs

### General Description

The ACQ/ACTQ574 is a high-speed, low-power octal D-type flip-flop with a buffered Common Clock (CP) and a buffered common Output Enable ( $\overline{OE}$ ). The information presented to the D inputs is stored in the flip-flops on the LOW-to-HIGH clock (CP) transition.

ACQ/ACTQ574 utilizes FACT Quiet Series™ technology to guarantee quiet output switching and improve dynamic threshold performance. FACT Quiet Series features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

The ACQ/ACTQ574 is functionally identical to the ACTQ374 but with different pin-out.

### Features

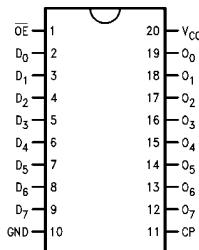
- $I_{CC}$  and  $I_{OZ}$  reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Inputs and outputs on opposite sides of the package allowing easy interface with microprocessors
- Functionally identical to the ACQ/ACTQ374
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Faster prop delays than the standard AC/ACT574

### Ordering Code:

Order Number	Package Number	Package Description
74ACQ574SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACQ574SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACQ574PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
74ACTQ574SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACTQ574SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ACTQ574PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Device also available in Tape and Reel. Specify by appending suffix "X" to the ordering code.

### Connection Diagram

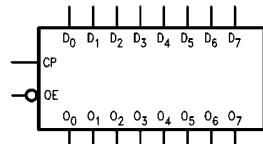


### Pin Descriptions

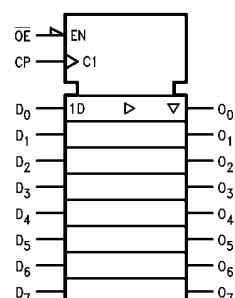
Pin Names	Description
D <sub>0</sub> -D <sub>7</sub>	Data Inputs
CP	Clock Pulse Input
$\overline{OE}$	3-STATE Output Enable Input
O <sub>0</sub> -O <sub>7</sub>	3-STATE Outputs

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## Logic Symbols



IEEE/IEC



## Functional Description

The ACQ/ACTQ574 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D-type inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable ( $\overline{OE}$ ) LOW, the contents of the eight flip-flops are available at the outputs. When  $\overline{OE}$  is HIGH, the outputs go to the high impedance state. Operation of the  $\overline{OE}$  input does not affect the state of the flip-flops.

## Function Table

$\overline{OE}$	Inputs			Internal	Outputs	Function
	CP	D	Q			
H	H	L	NC	Z	Hold	
H	H	H	NC	Z	Hold	
H	✓	L	L	Z	Load	
H	✓	H	H	Z	Load	
L	✓	L	L	L	Data Available	
L	✓	H	H	H	Data Available	
L	H	L	NC	NC	No Change in Data	
L	H	H	NC	NC	No Change in Data	

H = HIGH Voltage Level

L = LOW Voltage Level

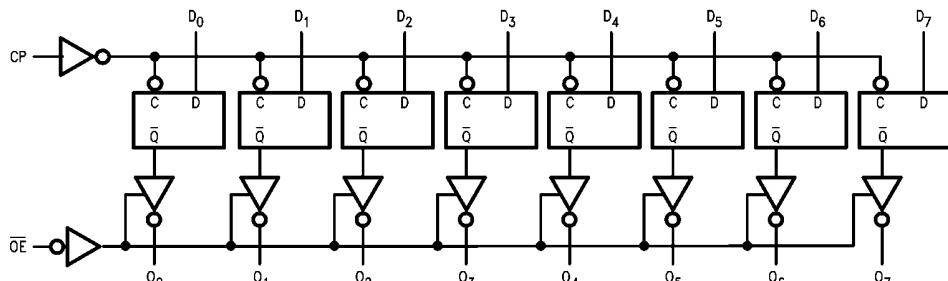
X = Immortal

Z = High Impedance

✓ = LOW-to-HIGH Transition

NC = No Change

## Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

<b>Absolute Maximum Ratings</b> (Note 1)			<b>Recommended Operating Conditions</b>			
Supply Voltage ( $V_{CC}$ )	-0.5V to +7.0V		Supply Voltage ( $V_{CC}$ )			
DC Input Diode Current ( $I_{IK}$ )			ACQ	2.0V to 6.0V		
$V_I = -0.5V$	-20 mA		ACTQ	4.5V to 5.5V		
$V_I = V_{CC} + 0.5V$	+20 mA		Input Voltage ( $V_I$ )	0V to $V_{CC}$		
DC Input Voltage ( $V_I$ )	-0.5V to $V_{CC} + 0.5V$		Output Voltage ( $V_O$ )	0V to $V_{CC}$		
DC Output Diode Current ( $I_{OK}$ )			Operating Temperature ( $T_A$ )	-40°C to +85°C		
$V_O = -0.5V$	-20 mA		Minimum Input Edge Rate $\Delta V/\Delta t$			
$V_O = V_{CC} + 0.5V$	+20 mA		ACQ Devices			
DC Output Voltage ( $V_O$ )	-0.5V to $V_{CC} + 0.5V$		$V_{IN}$ from 30% to 70% of $V_{CC}$			
DC Output Source or Sink Current ( $I_O$ )		±50 mA	$V_{CC}$ @ 3.0V, 4.5V, 5.5V	125 mV/ns		
DC $V_{CC}$ or Ground Current per Output Pin ( $I_{CC}$ or $I_{GND}$ )		±50 mA	Minimum Input Edge Rate $\Delta V/\Delta t$			
Storage Temperature ( $T_{STG}$ )	-65°C to +150°C		ACTQ Devices			
DC Latch-Up Source or Sink Current		±300 mA	$V_{IN}$ from 0.8V to 2.0V			
Junction Temperature ( $T_J$ )		140°C	$V_{CC}$ @ 4.5V, 5.5V	125 mV/ns		
PDIP			Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.			
<b>DC Electrical Characteristics for ACQ</b>						
Symbol	Parameter	$V_{CC}$ (V)	$T_A = +25^\circ C$		Units	Conditions
			Typ	Guaranteed Limits		
$V_{IH}$	Minimum HIGH Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	2.1 3.15 3.85	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
	Maximum LOW Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	0.9 1.35 1.65		
	$V_{OH}$	Minimum HIGH Level Output Voltage	3.0 4.5 5.5	2.99 4.49 5.49		
$V_{OL}$		Maximum LOW Level Output Voltage	3.0 4.5 5.5	2.56 3.86 4.86	V	$V_{IN} = V_{IL}$ or $V_{IH}$ $I_{OH} = -12\text{ mA}$ $I_{OH} = -24\text{ mA}$ $I_{OH} = -24\text{ mA}$ (Note 2)
			3.0 4.5 5.5	2.46 3.76 4.76		
	0.002 0.001 0.001		0.1 0.1 0.1	$I_{OUT} = 50\text{ }\mu A$		
$I_{IN}$ (Note 4)	Maximum Input Leakage Current	5.5	±0.1	±1.0	$\mu A$	$V_I = V_{CC}, \text{ GND}$
	Minimum Dynamic	5.5		75		
	Output Current (Note 3)	5.5		-75		
$I_{CC}$ (Note 4)	Maximum Quiescent Supply Current	5.5	4.0	40.0	$\mu A$	$V_{IN} = V_{CC}$ or GND
	Maximum 3-STATE Leakage Current	5.5	±0.25	±2.5		$V_I (\text{OE}) = V_{IL}, V_{IH}$ $V_I = V_{CC}, \text{ GND}$ $V_O = V_{CC}, \text{ GND}$





### AC Operating Requirements for ACTQ

Symbol	Parameter	V <sub>CC</sub> (V) (Note 18)	T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = -40°C to +85°C C <sub>L</sub> = 50 pF	Units
			Typ	Guaranteed Minimum		
t <sub>S</sub>	Setup Time, HIGH or LOW D <sub>n</sub> to CP	5.0	0	3.0	3.0	ns
t <sub>H</sub>	Hold Time, HIGH or LOW D <sub>n</sub> to CP	5.0	0	1.5	1.5	ns
t <sub>W</sub>	CP Pulse Width, HIGH or LOW	5.0	2.0	4.0	4.0	ns

Note 18: Voltage Range 5.0 is 5.0V ± 0.5V

### Capacitance

Symbol	Parameter	Typ	Units	Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = OPEN
C <sub>PD</sub>	Power Dissipation Capacitance	40.0	pF	V <sub>CC</sub> = 5.0V

## FACT Noise Characteristics

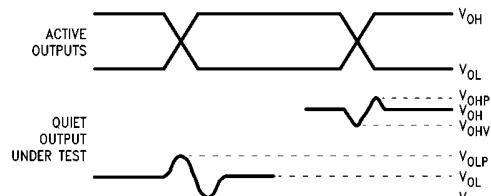
The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

### Equipment:

Hewlett Packard Model 8180A Word Generator  
PC-163A Test Fixture  
Tektronics Model 7854 Oscilloscope

### Procedure:

1. Verify Test Fixture Loading: Standard Load 50 pF, 500Ω.
2. Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
4. Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
5. Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



Note 19:  $V_{OHV}$  and  $V_{OLP}$  are measured with respect to ground reference.

Note 20: Input pulses have the following characteristics:  $f = 1$  MHz,  $t_r = 3$  ns,  $t_f = 3$  ns, skew < 150 ps.

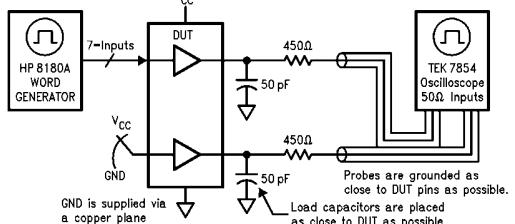
**FIGURE 1. Quiet Output Noise Voltage Waveforms**

$V_{OLP}/V_{OLV}$  and  $V_{OHP}/V_{OHV}$ :

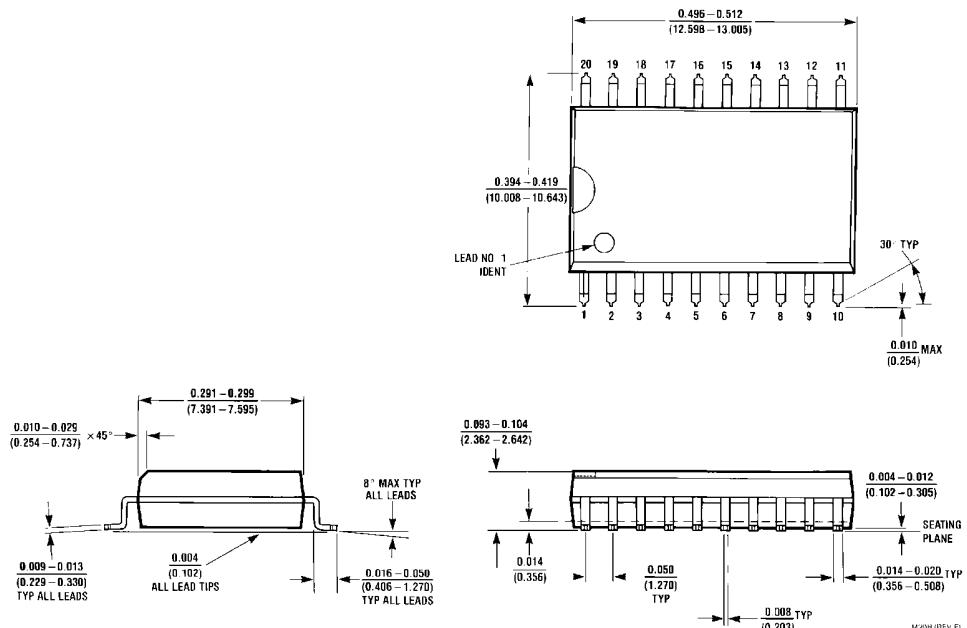
- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure  $V_{OLP}$  and  $V_{OLV}$  on the quiet output during the worst case for active and enable transition. Measure  $V_{OHP}$  and  $V_{OHV}$  on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

$V_{ILD}$  and  $V_{IHD}$ :

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level,  $V_{IL}$ , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds  $V_{IL}$  limits, or on output HIGH levels that exceed  $V_{IH}$  limits. The input LOW voltage level at which oscillation occurs is defined as  $V_{ILD}$ .
- Next decrease the input HIGH voltage level,  $V_{IH}$ , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds  $V_{IL}$  limits, or on output HIGH levels that exceed  $V_{IH}$  limits. The input HIGH voltage level at which oscillation occurs is defined as  $V_{IHD}$ .
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

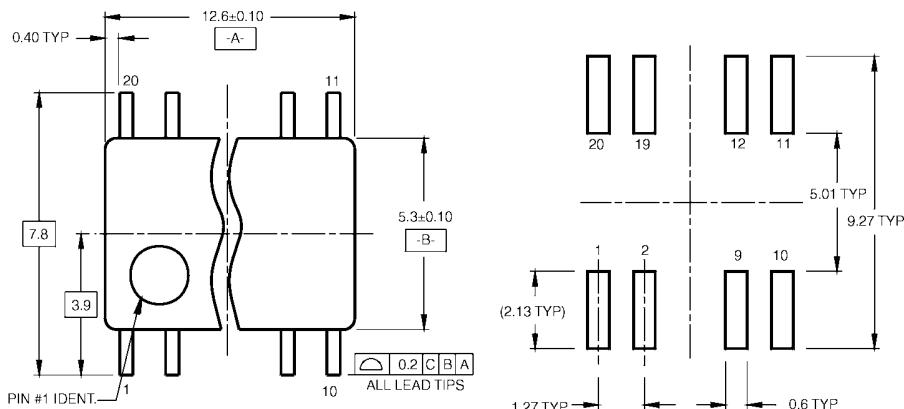


**FIGURE 2. Simultaneous Switching Test Circuit**

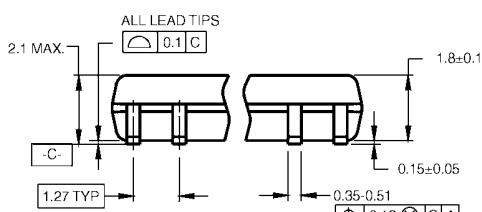
**Physical Dimensions** inches (millimeters) unless otherwise noted

20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body  
Package Number M20B

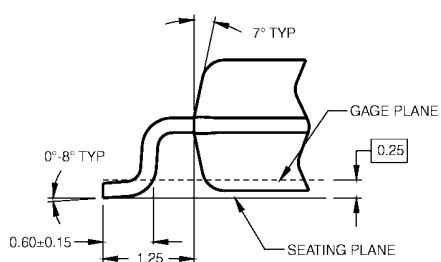
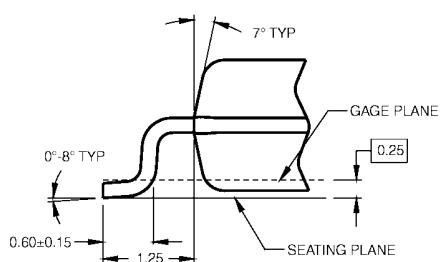
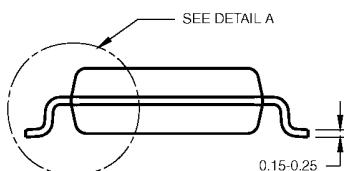
**Physical Dimensions** inches (millimeters) unless otherwise noted (Continued)



LAND PATTERN RECOMMENDATION



DIMENSIONS ARE IN MILLIMETERS



NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION,  
ESTABLISHED IN DECEMBER, 1998.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD  
FLASH, AND TIE BAR EXTRUSIONS.

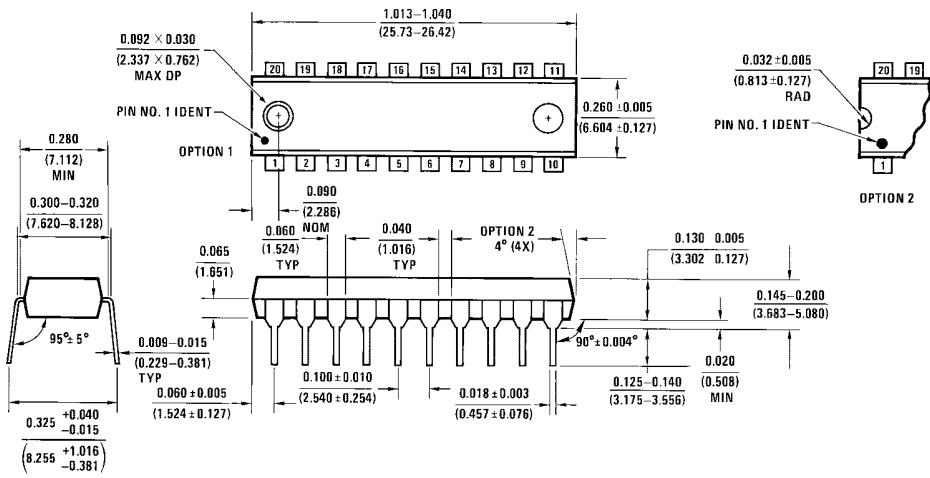
M20DRevB1

DETAIL A

**20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide  
Package Number M20D**

## 74ACQ574 • 74ACTQ574 Quiet Series™ Octal D-Type Flip-Flop with 3-STATE Outputs

### Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



N20A (REV G)

20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide  
Package Number N20A

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